## Notice of References Cited Application/Control No. 10/706,749 Examiner Matthew G. Kayrish Applicant(s)/Patent Under Reexamination FURUYA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,044,057	03-2000	Park et al.	720/675
	В	US-			
	С	US-			
	D	US-	·		
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	Κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

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